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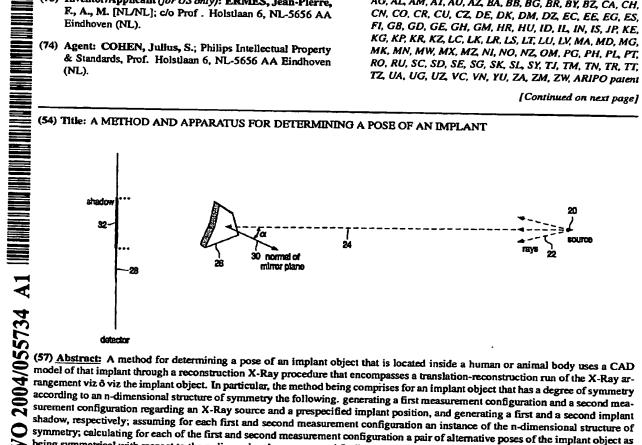
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Declaration under Rule 4.17:

as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE,



shadow, respectively; assuming for each first and second measurement configuration an instance of the n-dimensional structure of symmetry; calculating for each of the first and second measurement configuration a pair of alternative poses of the implant object as being symmetrical with respect to the n-dimensional structure; and finding among the pairs of alternative poses two matching poses that thereby produce an angle information with respect to the n-dimensional structure of symmetry.